

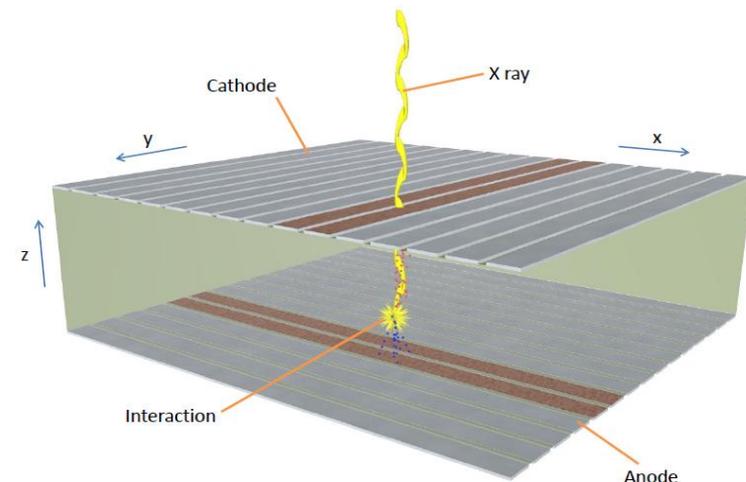
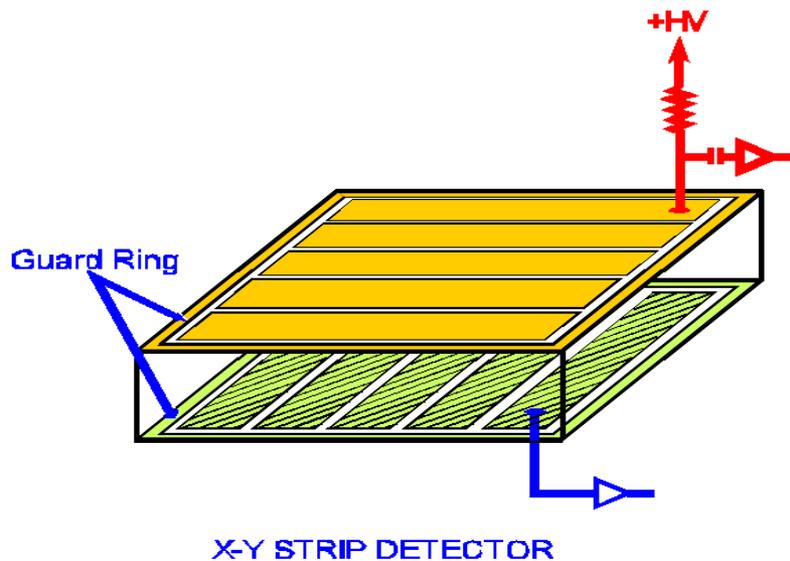
# Phenix-Volga: Germanium Double Sided Strip Detector development program at IRAP



Odile Cœur-Joly  
(On behalf of Phenix-Volga's team)

- To study a new generation of detector, intended to be placed at the focal point of a hard X-ray telescope
  - high energy and spatial resolution
  - broad X-ray coverage up to 200 keV
  - 3D localization capabilities
- To achieve a good level of qualification and Test Readiness of the detection system (space context)

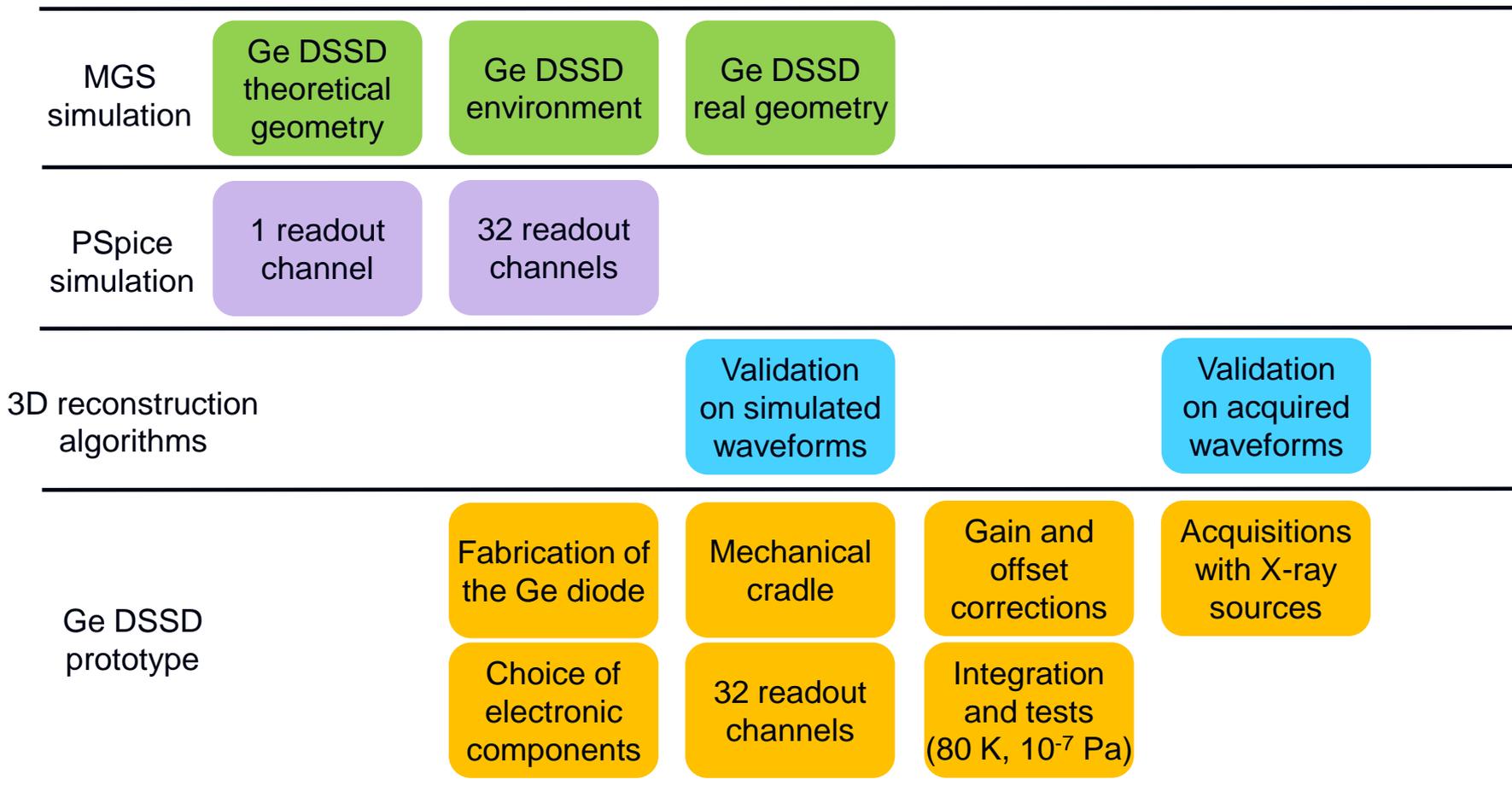
- High purity Germanium HPGe diode
- Planar Double Sided Strip Detector (DSSD)
  - 3D spatial localization of the photon interaction
  - $N \times N$  pixels with only  $2 \times N$  electronic channels



- The Ge DSSD was initially part of the PheniX proposal, submitted to ESA for its mission M3 in 2010, but not selected.
- R&T phase 1 program, funded by CNES (sept 2011 – dec 2012)
- R&T phase 2 program, funded by CNES (jan 2013 – april 2014)
- *3rd R&T program, submitted to CNES (answer january 2014)*
- *Future work : full detector demonstrator (> 2015)*

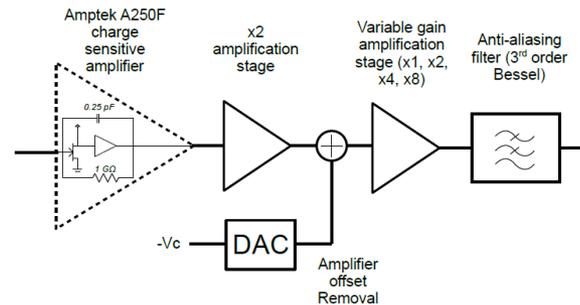
- **Main objectives:**
  - Improve our understanding of the Ge DSSD
  - Achieve a 3D digital reconstruction of the photon interactions
  - Design a whole detection system with a Ge DSSD
- **Developments:**
  - Simulation of the Ge DSSD response (*presentation of Isidre Mateu*)
  - Simulation of the analog electronic chain
  - 3D reconstruction algorithms (*presentation of Isidre Mateu*)
  - Ge DSSD prototype with 32 (16\*2) electronic channels

- R&T phase 1: sequence of actions

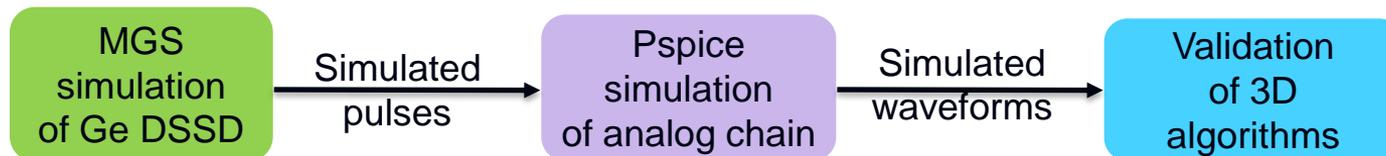


- Simulation of the Ge DSSD with MGS software
  - *(see next presentation of Isidre Mateu)*
  - Provides good knowledge of the diode and its context
    - ▶ the geometry of the strips
    - ▶ the influence of the metal parts of the cradle on the Diode
    - ▶ the guard ring properties
  - The simulated pulses generated by MGS have been used as inputs for the analog electronic chain simulation

- Validation of 3D algorithms on simulated data
  - The analog chain has been simulated with an Amptek A250F charge sensitive amplifier (A250 + JFET)



- The simulated waveforms have been used as inputs for 3D algorithms until the Ge DSSD prototype is finished

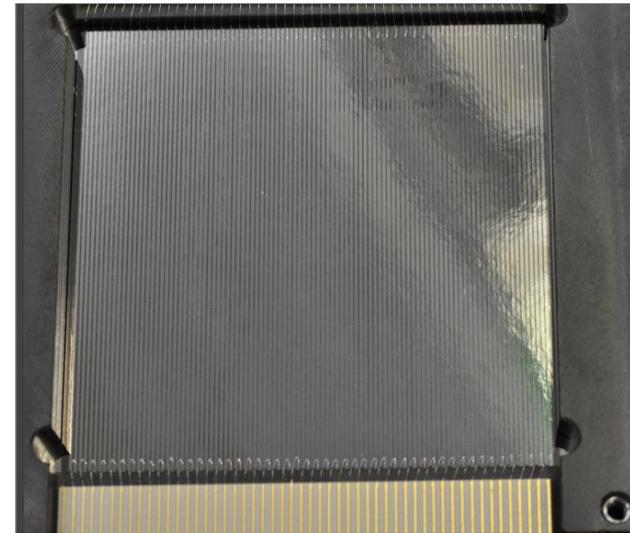


- Development of a Ge DSSD prototype with 32 channels
  - Processing of the 100X-100Y Ge diode
  - Mechanical integration of the diode
  - Qualification of the Ge diode process
  - Development of 32 electronic channels
  - Integration in the cryostat

- Processing of the 100X-100Y Ge diode by Canberra (Lingolsheim, France)
  - ▶ 100X-100Y, 350  $\mu\text{m}$  wide strips, gap of 50  $\mu\text{m}$
  - ▶ 50 even strips, 50 odd strips for one face, same for the perpendicular strips of the back face



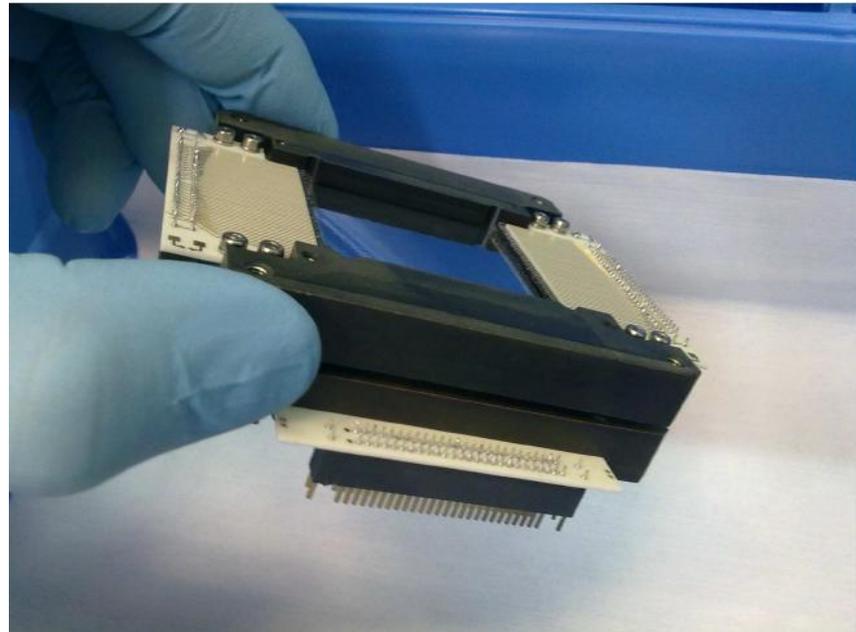
Cristal: 51x51 mm, thickness = 11.7 mm  
Detection area: 40x40 mm



Bondings of 50 strips in one PCB

- **Mechanical integration of the diode**
  - Choice of a cradle prototype in Vespel, good insulator, non metallic, not intended to pass vibration tests
  - use of 64 pins qualified connectors (Omnetics)

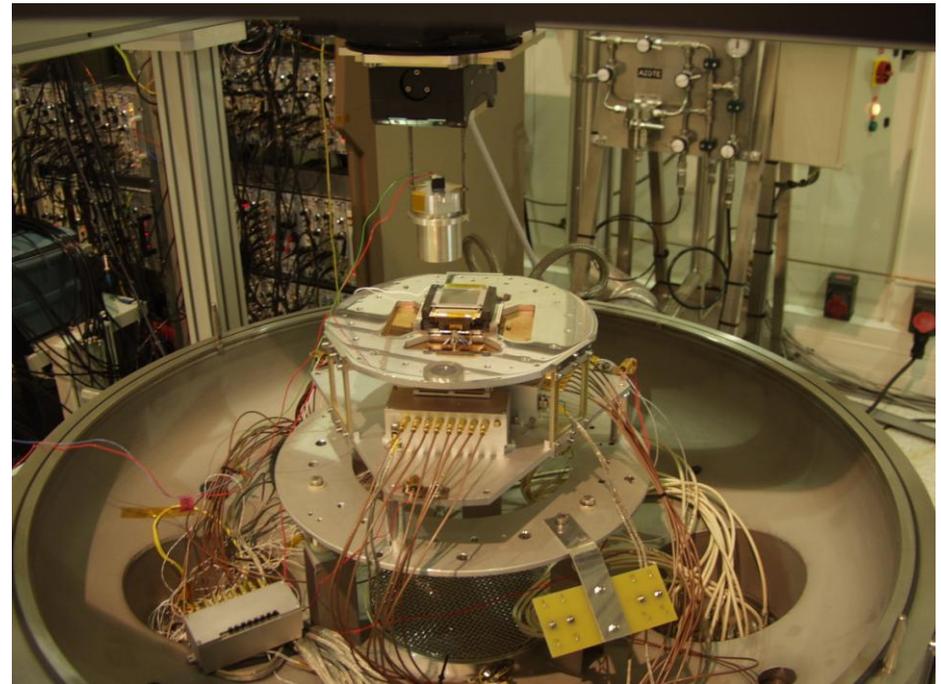
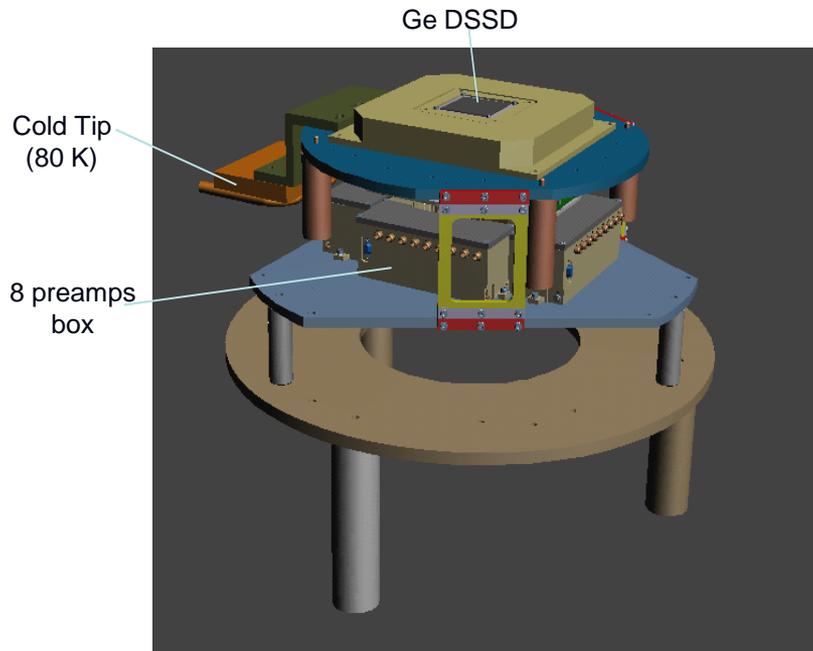
Material : Vespel  
XY plane = 75x75 mm  
Thickness = 35 mm



- Qualification of the Ge diode fabrication process
  - ▶ 30 thermal cycles (-200°C - +80°C)
  - ▶ Several openings of the cryostat (air)
  - ▶ Leakage current OK
  - ▶ Tension of depletion of 1700 V
  
  - ▶ *2 complete disassembly to repair the bondings*

- **Development of the 32 electronic channels**
  - Choice of the Amptek A250F charge sensitive amplifier (A250 + JFET)
    - ▶ A250 already qualified for ESA
    - ▶ Less noise if the A250F is cooled (0.7 keV at -80°C)
  - Choice of an early digitization of the signal
    - ▶ The gain and correction offset stages are located outside the cryostat (David Murat, IRAP)
    - ▶ The ADC stage is provided by a COTS 32 channels digitizer (N6740, 62.5 MHz, CAEN, Italy)
    - ▶ The waveforms provided by the digitizer are analysed **offline** by the 3D reconstruction algorithms

- Integration of the Ge DSSD and the 32 electronic channels into the cryostat of SPI Integral, at IRAP
  - ▶ Ge DSSD : 103 K,  $3.10^{-7}$  mbar

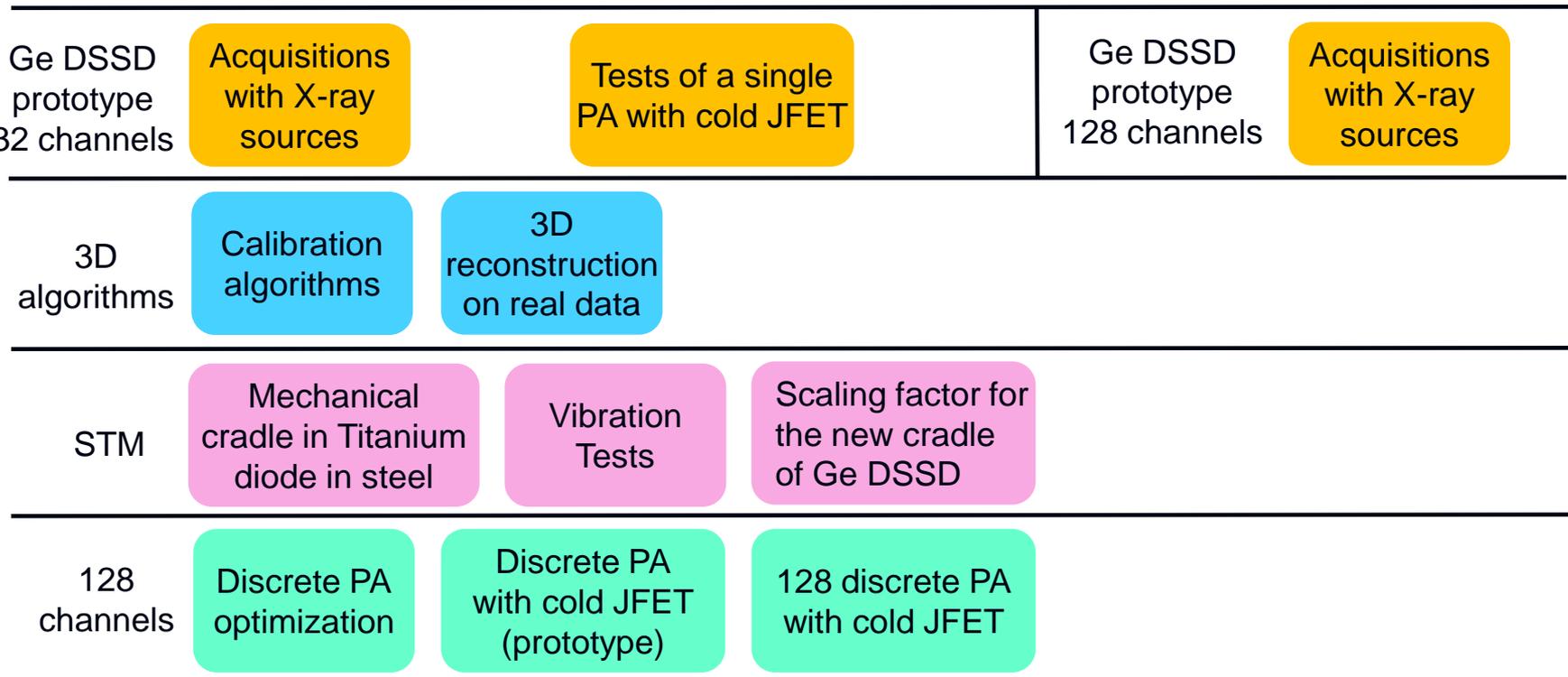


- Phase 1 : conclusions
  - Validation of Ge DSSD and electronic chain simulations
  - Validation of the 3D algorithms on simulated data
  - Qualification of the Ge diode process
  - Half qualification of the front-end electronic chain
    - ▶ Connectics OK, A250 OK, JFET to be done
  - *The diode cradle can not pass vibration tests*
  - *The electronic chain has to be improved*

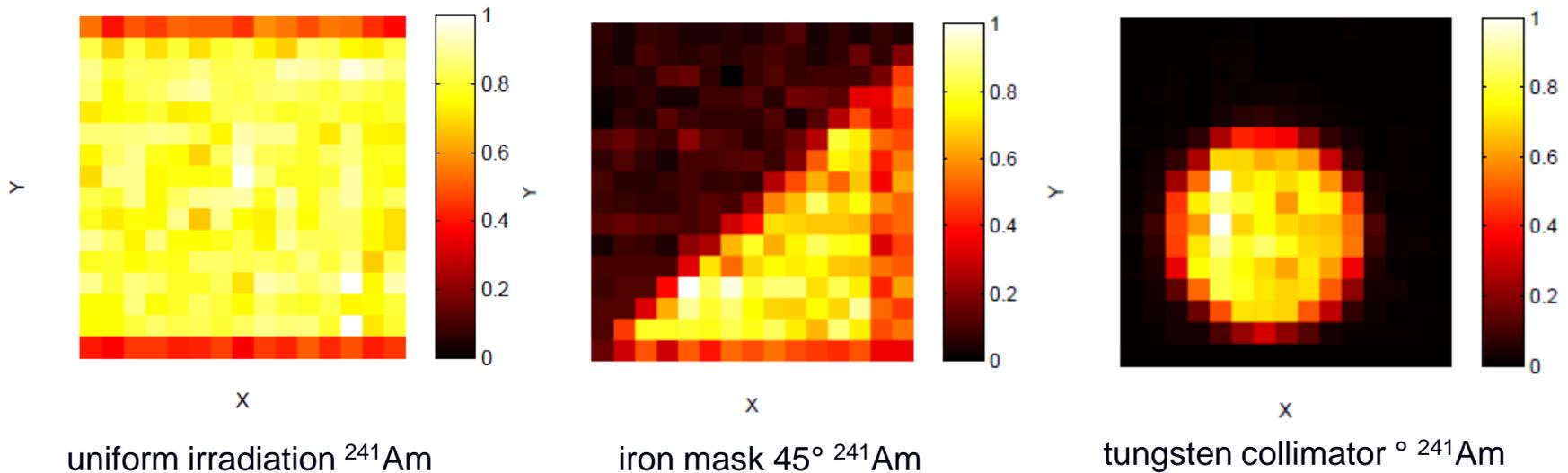
**→ R&T phase 2 accepted by CNES, started on january 2013**

- **Main objectives:**
  - Validate the 3D algorithms on real data (first prototype)
  - Increase the Test Readiness Level (TRL) of the detector system
  - Reduce the noise of the electronic chain
  - Increase the detection area of the Ge DSSD
- **Developments:**
  - Calibration algorithms
  - STM to pass the vibrations tests specified by ESA
  - Discrete preamplifiers with cold JFET
  - Transition from 32 to 128 electronic channels

- R&T phase 2: sequence of actions



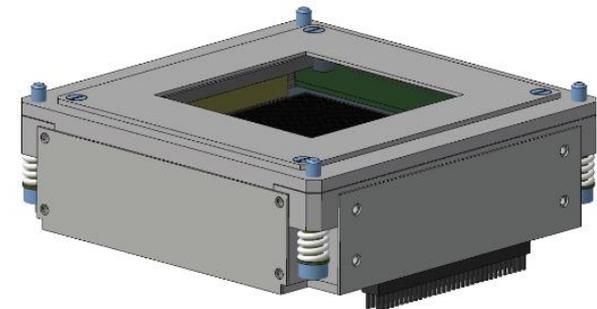
- Validation of 3D algorithms
  - Use of the Ge DSSD prototype with 32 channels
  - 16\*2 channels = 16\*16 (256) pixels of 350  $\mu\text{m}$
  - Results in next presentation of I.Mateu



- **STM of the detector assembly**

- Cradle in Titanium, for its thermal conductivity and sturdiness
- Fake diode in steel of 90x90x15 mm, same size as a detector in a space telescope
- Mechanical clamping only on the 2 faces, 90 DaN to the diode
- Vibration levels recommended by ECSS for a spatial prototype
  - ▶  $rdr = 0,5 \text{ g}$
  - ▶ sine 3 axes = 20 g
  - ▶ random X = 24,32 g r.m.s.
  - ▶ random Y,Z = 15,69 g r.m.s.

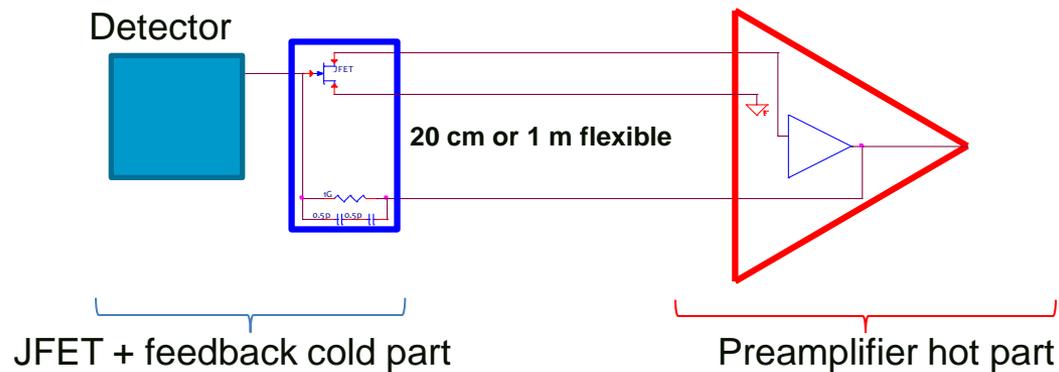
**→ Tests passed successfully**



**78 x 78 x 23 mm**

- Scaling factor for the design of the functional Ge DSSD cradle

- **New design for the 128 electronic channels**
  - Choice of a discrete preamplifier (high cost of A250)
  - Choice of a PA with separated JFET



- Advantages to separate the JFET from the PA
  - Shortening the JFET - detector connection (less noise)
  - Increasing the JFET - PA connection (up to 1 meter)
    - ▶ Outside the anti coincidence shielding
  - Cooling the JFET to decrease the noise becomes possible
  - No need to cool the PA at  $-80^{\circ}\text{C}$ , use of a flexible connection
    - ➔ **JFET (130 K) and PA (25°C): < 0.2 keV expected**
- Drawbacks
  - JFETs consume more cold power
  - The capacitors near to the JFET must also be cooled on the High Voltage side

- **Transition from 32 to 128 channels**
  - Reduction of the cost of the components
  - Cooling power improvement, thermal leakage reduction
  - Miniaturization to optimize the available space

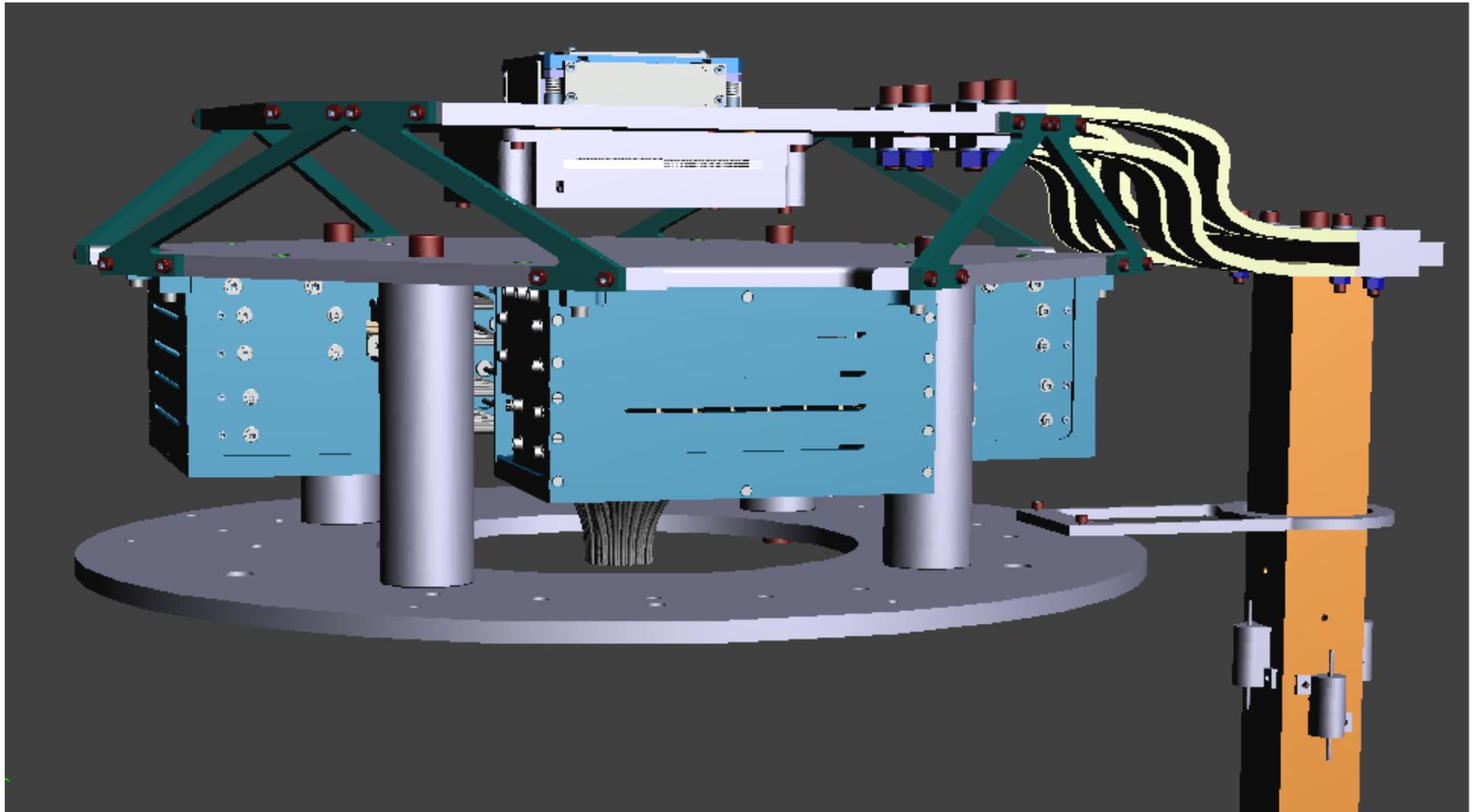


PT cryocooler



32 Preamplifiers in one box

- Assembly for the Ge DSSD 128 channels (64\*64 pixels)



- Phase 2 : conclusions
  - TRL 4.5 reached on the detector mechanical assembly
  - Detection area increased up to 25\*25 mm (64\*64 pixels)
  - Low-noise electronic chain with cold JFET
  
  - *Thermal validation of the detector system to be done*
  - *Qualification of the analog electronic chain to be done*
  - *Minimal size with discrete components already reached*

**→ R&T phase 3 submitted to CNES**

- **Main objectives:**
  - Characterization of the Ge DSSD with 128 channels working prototype
  - Reduction of the mass and power budget of the detector assembly
- **Developments:**
  - Hybridation of 128 PA components
  - Hybridation of 32 cold JFETs

**→ Selection of the R&T program phase 3 end of january 2014**

- **Main objectives:**
  - Production of a full detector demonstrator (200\*200 pixels)
  
- **Developments:**
  - Integration of the triggers, gain, correction offset into FPGAs
  - Integration of the 3D reconstruction algorithms into DSPs

**→ Fundings to be found**